

pn - Junctions

pn junctions

pn junctions are found in:

diodes

solar cells

LEDs

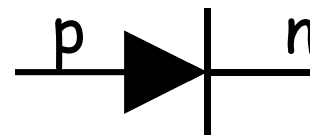
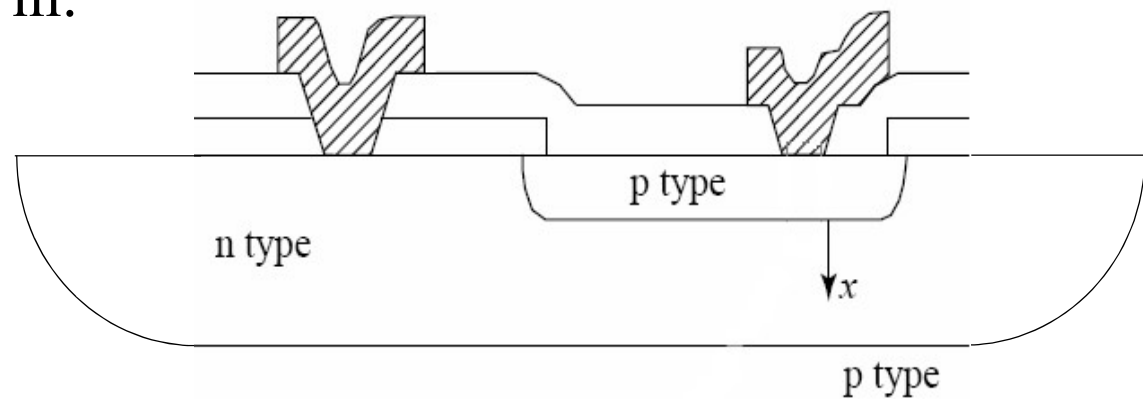
isolation

JFETs

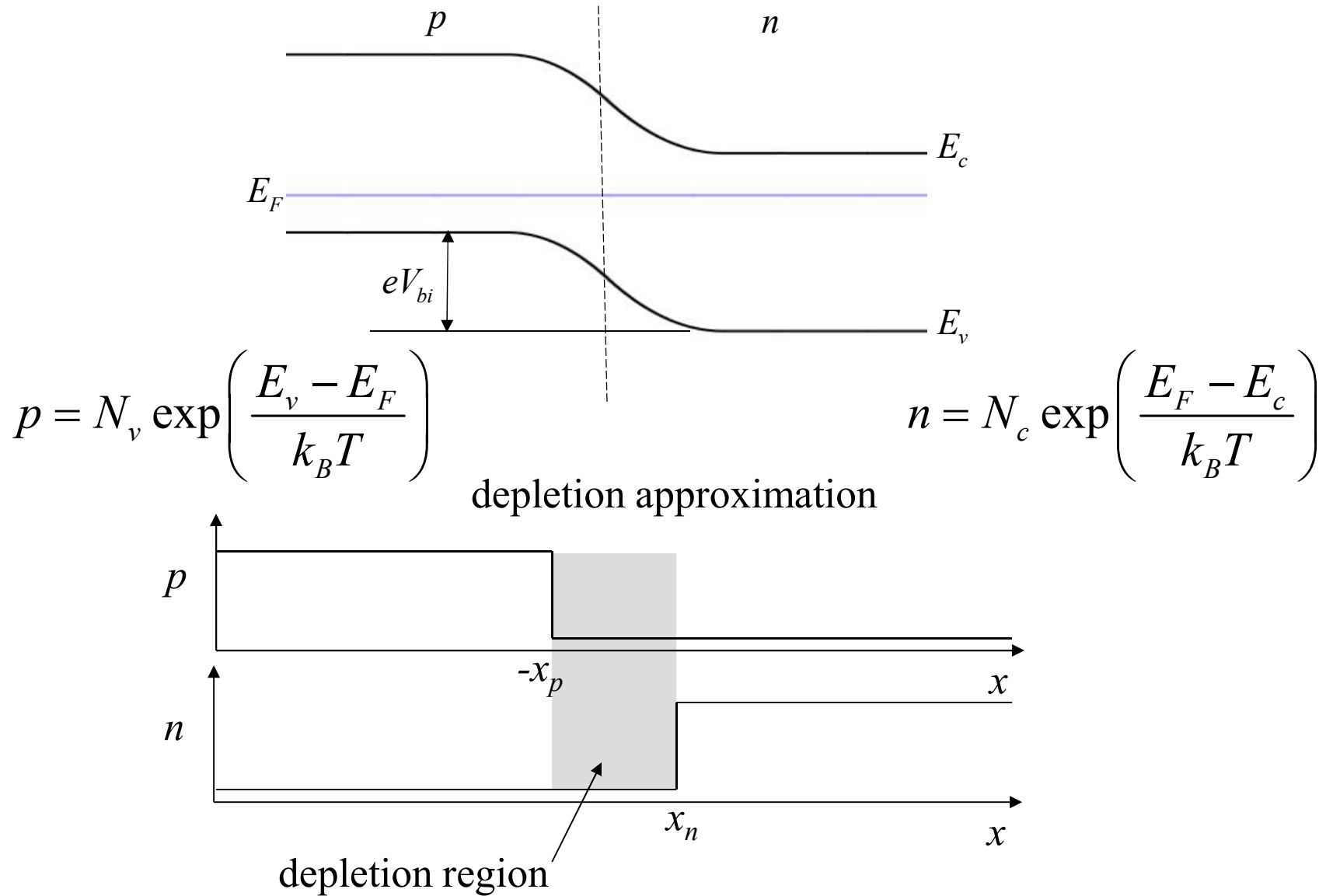
bipolar transistors

MOSFETs

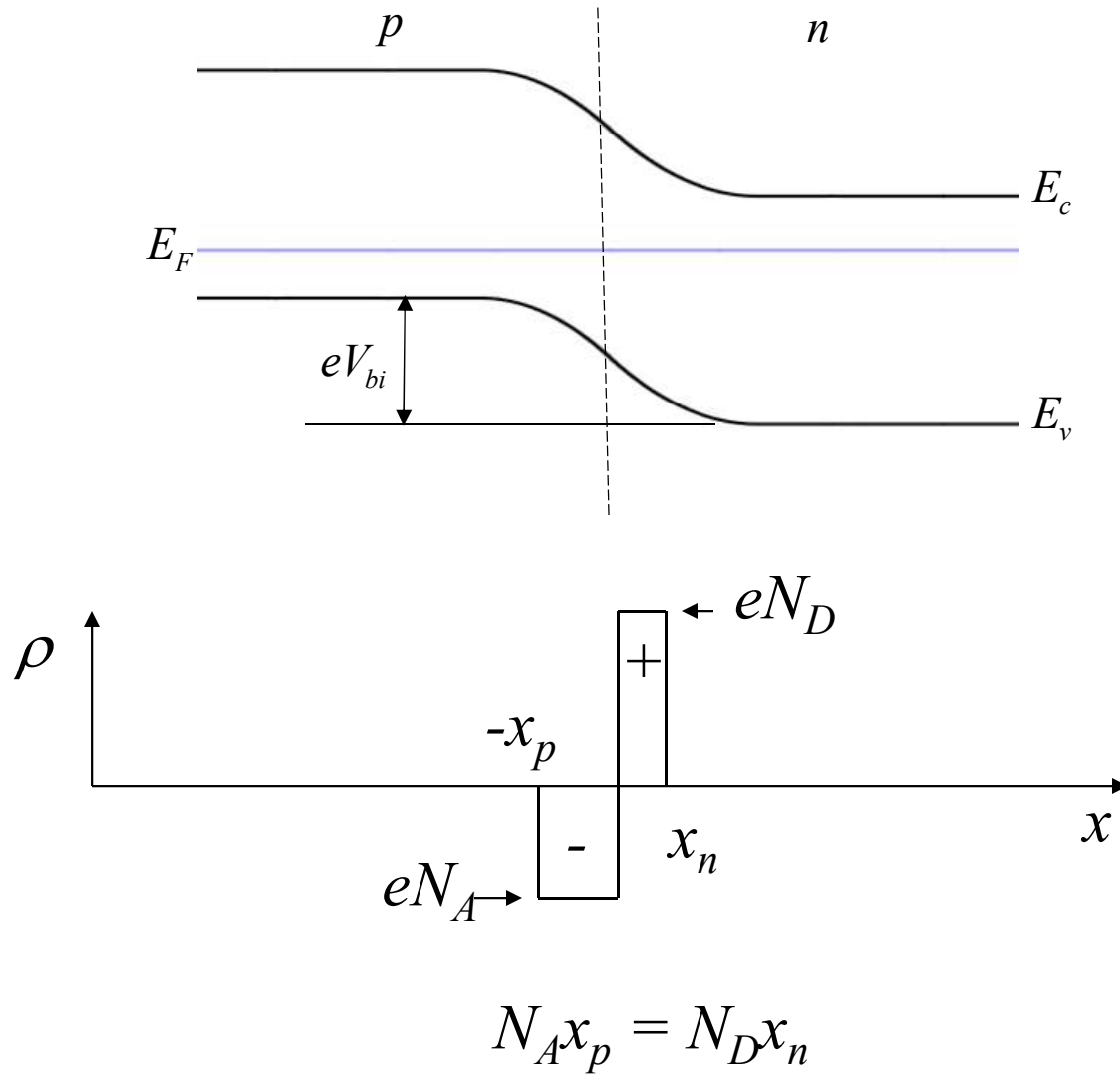
solid state lasers



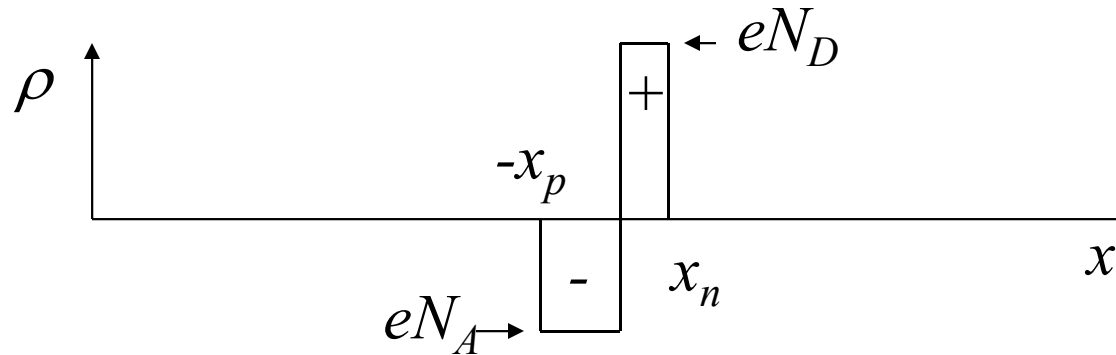
p and n profiles



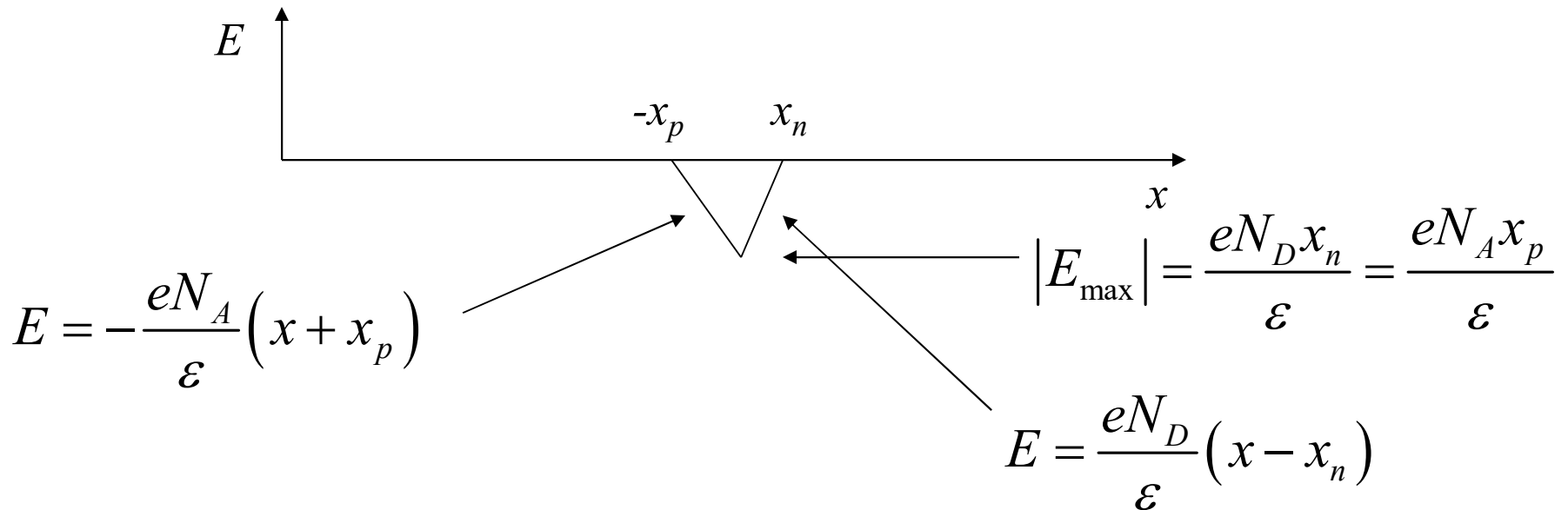
space charge



electric field

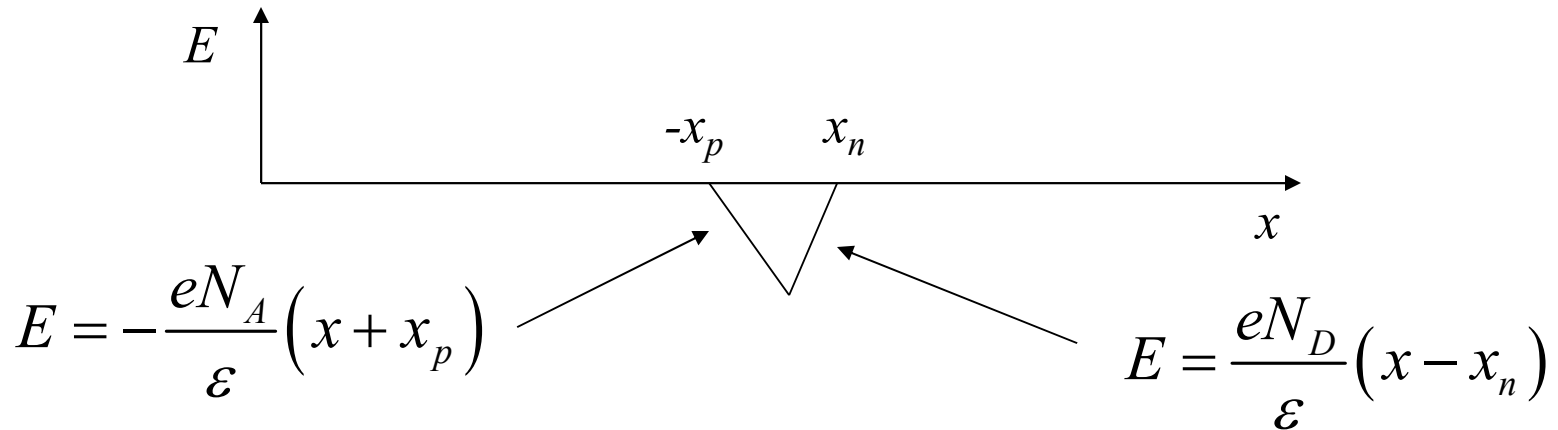


Gauss's law $\nabla \cdot \vec{E} = \frac{\rho}{\epsilon}$ in 1-D is $\frac{dE}{dx} = \frac{\rho}{\epsilon}$



E pushes the holes towards p and the electrons towards n

potential



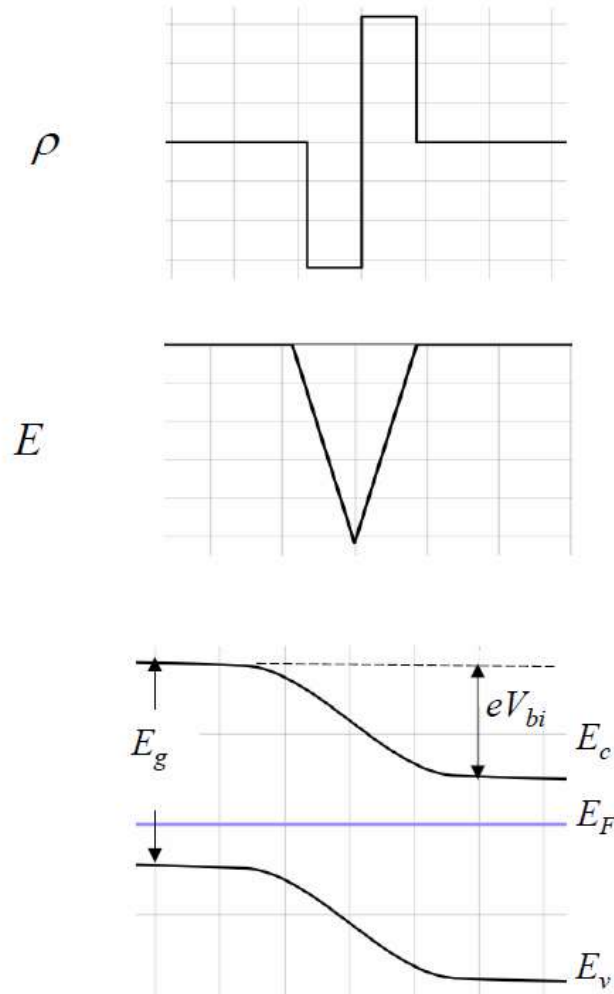
$$\frac{dV}{dx} = -E$$

$$V = \frac{eN_A}{\epsilon} \left(\frac{x^2}{2} + xx_p \right) \quad -x_p > x > 0$$

$$V = \frac{-eN_D}{\epsilon} \left(\frac{x^2}{2} - xx_n \right) \quad 0 > x > x_n$$

$$V(-x_p) = \frac{-eN_A}{2\epsilon} x_p^2 \quad V(0) = 0 \quad V(x_n) = \frac{eN_D}{2\epsilon} x_n^2$$

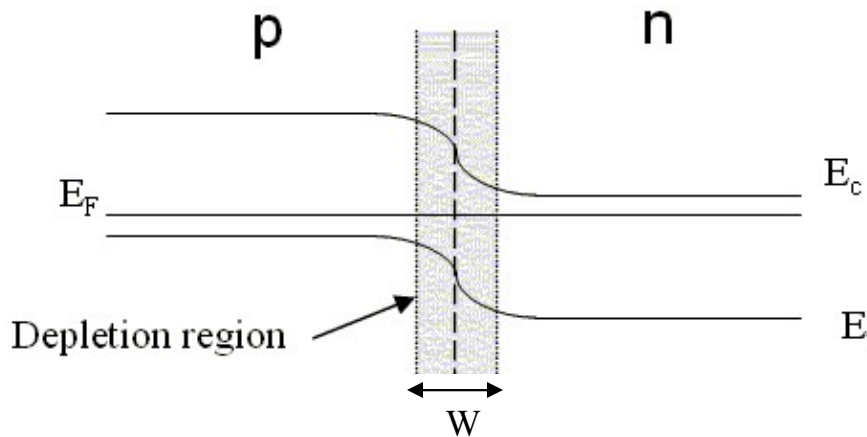
abrupt pn junction



$$V_{bi} = \frac{k_B T}{e} \ln \left(\frac{N_D N_A}{n_i^2} \right)$$

$$= \frac{e N_A x_p^2}{2\epsilon} + \frac{e N_D x_n^2}{2\epsilon}$$

Depletion width



$$V_{bi} = \frac{k_B T}{e} \ln \left(\frac{N_D N_A}{n_i^2} \right) = \frac{e N_A x_p^2}{2\epsilon} + \frac{e N_D x_n^2}{2\epsilon}$$

$$N_A x_p = N_D x_n = N_D (W - x_p) = N_A (W - x_n)$$

$$x_p = \frac{N_D W}{N_A + N_D}$$

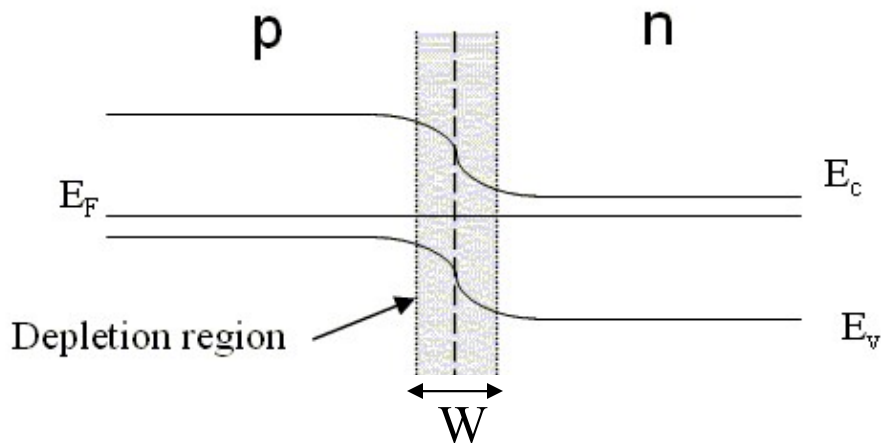
$$x_n = \frac{N_A W}{N_A + N_D}$$

$$V_{bi} = \frac{e}{2\epsilon} \frac{N_D N_A}{N_D + N_A} W^2$$

$$W = \sqrt{\frac{2\epsilon (N_D + N_A) V_{bi}}{e N_D N_A}}$$

light doping => wide depletion width

Depletion width



$$V_{bi} \sim 1\text{V}$$

$$W \sim 10\text{ nm} - 10\ \mu\text{m}$$

$$E_{max} \sim 10^4\ \text{V/cm}$$

The electric field pushes the electrons towards the n-region and the holes towards the p-region.

Diffusion sends electrons towards the p-region and holes towards the n-region.

Abrupt pn junctions in the depletion approximation

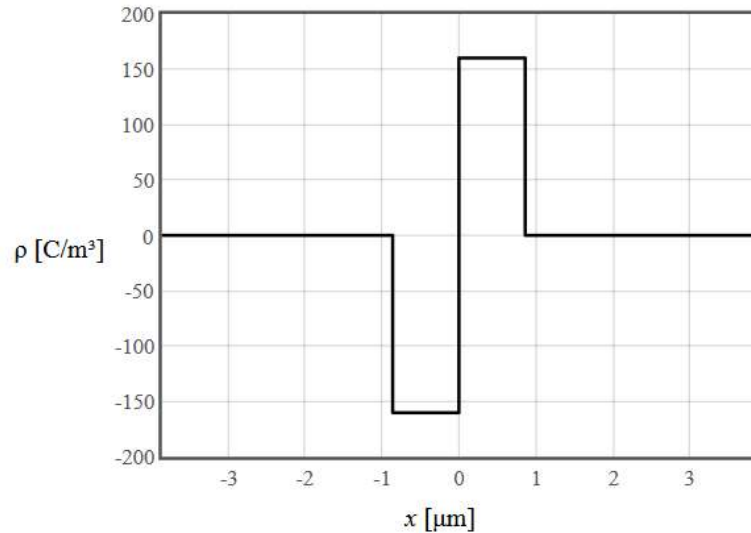
In an abrupt pn junction, the doping changes abruptly from p to n. It is common to solve for the band bending, the local electric field, the carrier concentration profiles, and the local conductivity in the depletion approximation. In this approximation it is assumed that there is a depletion width W around the transition from p to n where the charge carrier densities are negligible. Outside the depletion width the charge carrier densities are equal to the doping densities so that the semiconductor is electrically neutral outside the depletion width. Using this approximation it is possible to calculate the important properties of the pn junction.

$N_A =$ <input type="text" value="1E15"/> $1/\text{cm}^3$	$N_D =$ <input type="text" value="1E15"/> $1/\text{cm}^3$	$E_g =$ <input type="text" value="1.166-4.73E-4*T*(T+636)"/> eV
$N_v(300) =$ <input type="text" value="9.84E18"/> $1/\text{cm}^3$	$N_c(300) =$ <input type="text" value="2.78E19"/> $1/\text{cm}^3$	$\epsilon_r =$ <input type="text" value="12"/> $T =$ <input type="text" value="300"/> K
$\mu_p =$ <input type="text" value="480"/> $\text{cm}^2/\text{V s}$	$\mu_n =$ <input type="text" value="1350"/> $\text{cm}^2/\text{V s}$	$\tau_p =$ <input type="text" value="1E-10"/> s $\tau_n =$ <input type="text" value="1E-10"/> s
$V =$ <input type="text" value="-0.5"/> V		<input type="button" value="Submit"/>

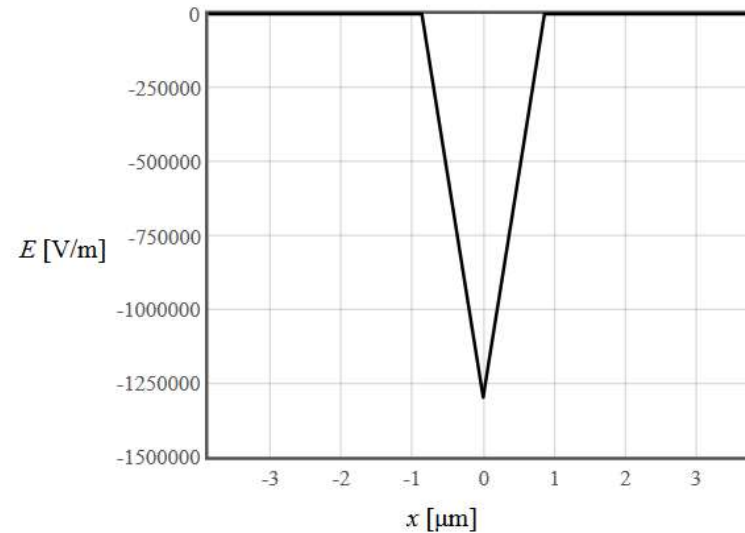
$$E_g = 1.12 \text{ eV} \quad W = 1.72 \text{ } \mu\text{m} \quad x_p = -0.861 \text{ } \mu\text{m} \quad x_n = 0.861 \text{ } \mu\text{m} \quad V_{bi} = 0.618 \text{ V} \quad C_j = 6.17 \text{ nF/cm}^2$$

$$D_p = 12.4 \text{ cm}^2/\text{s} \quad D_n = 34.9 \text{ cm}^2/\text{s} \quad L_p = 0.352 \text{ } \mu\text{m} \quad L_n = 0.591 \text{ } \mu\text{m}$$

Charge density



Electric field



diode fabrication

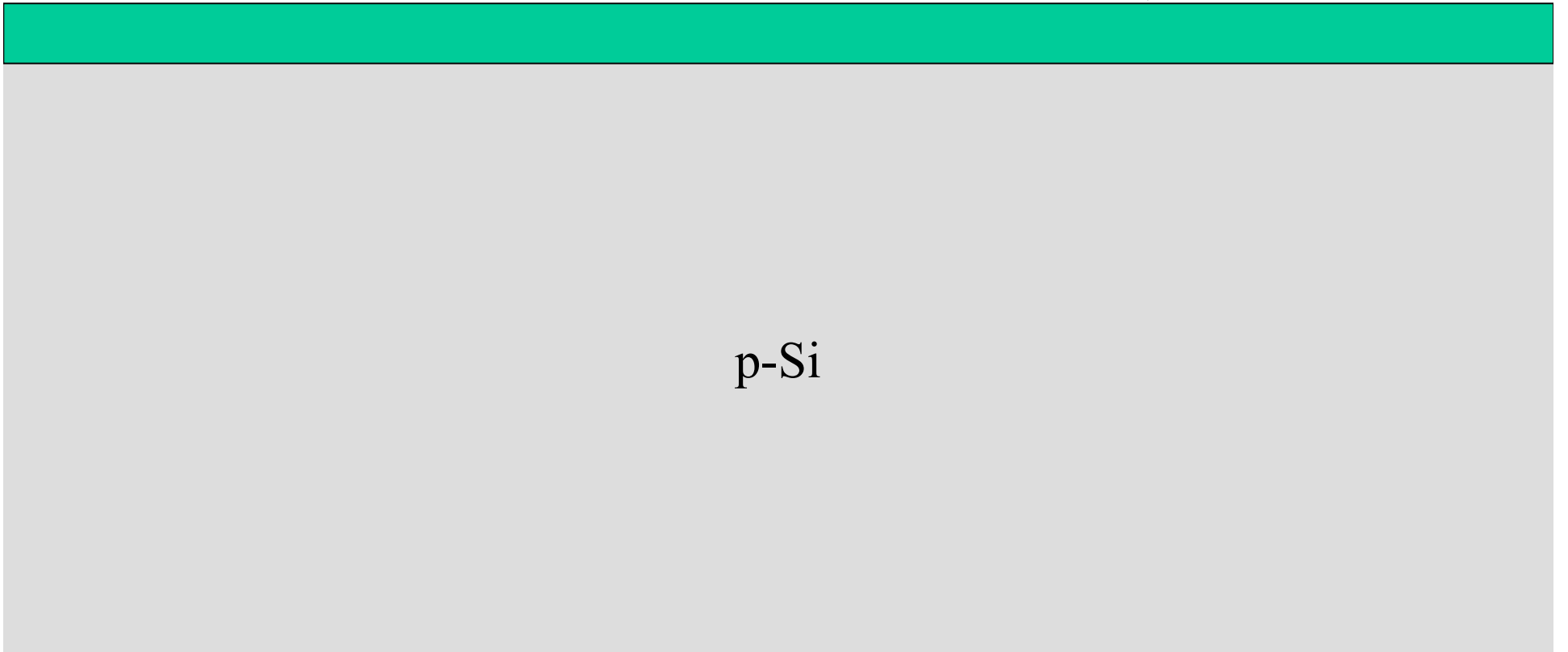
p-Si 100 wafer

CVD oxide

SiO_2



p-Si

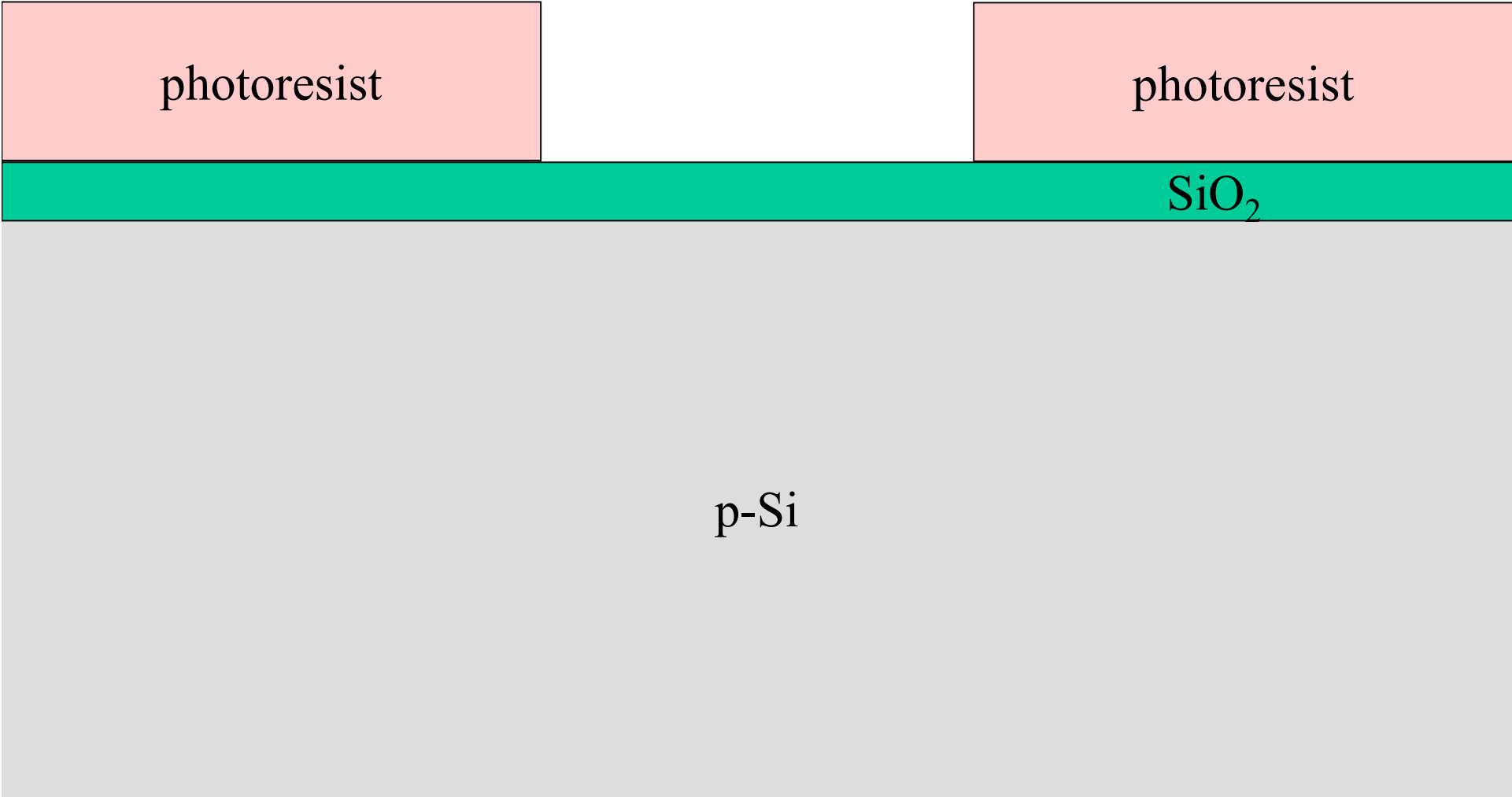


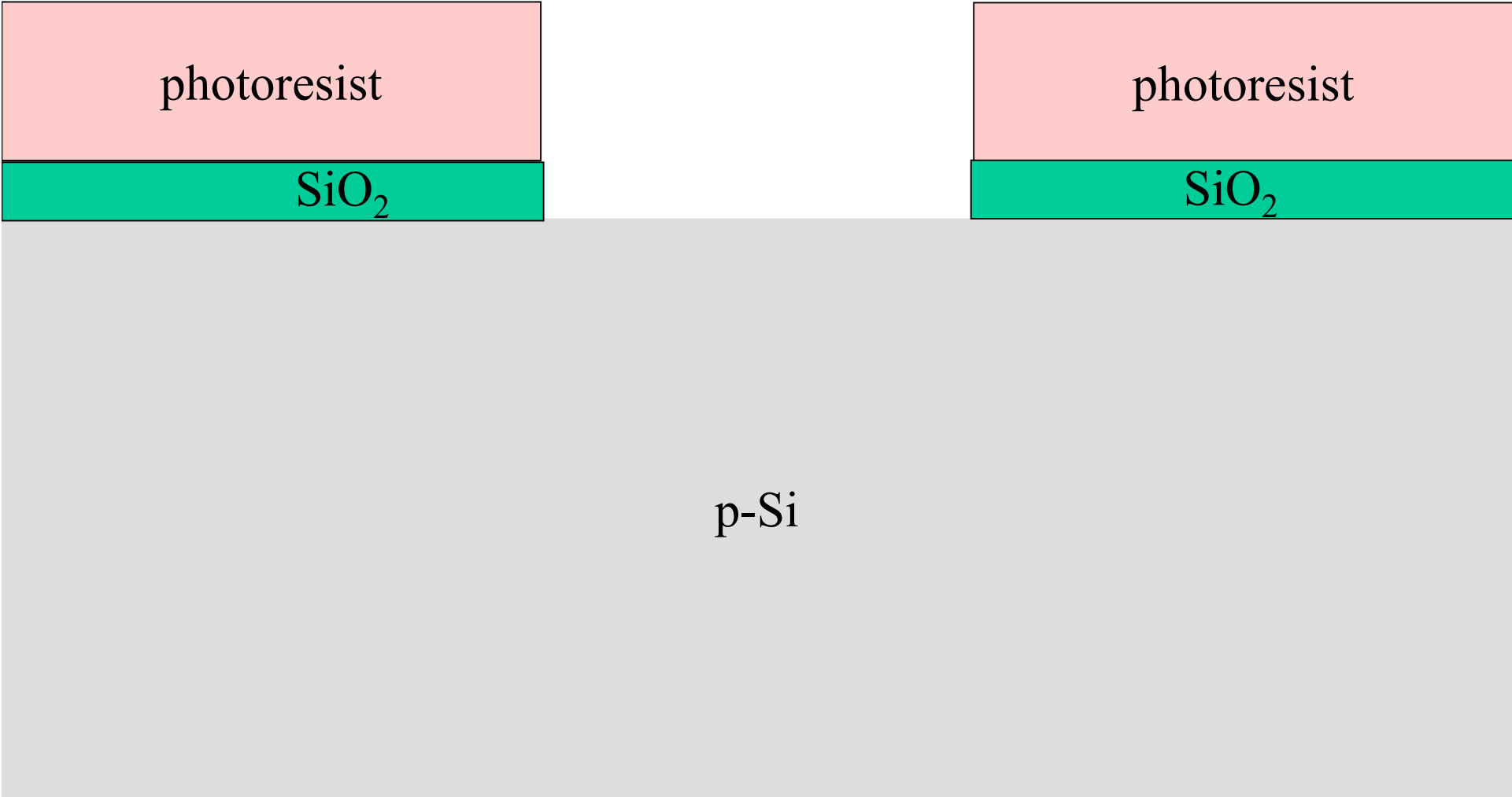


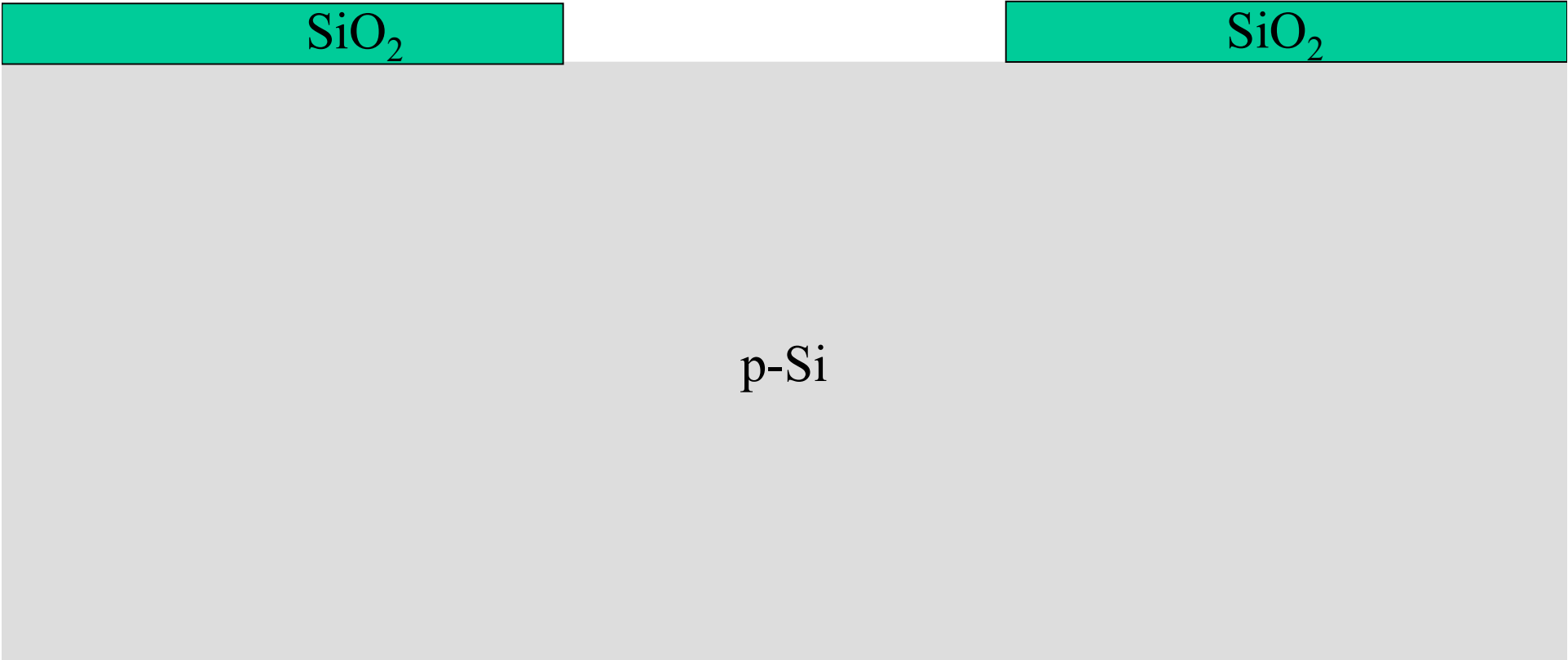
photoresist

SiO₂

p-Si





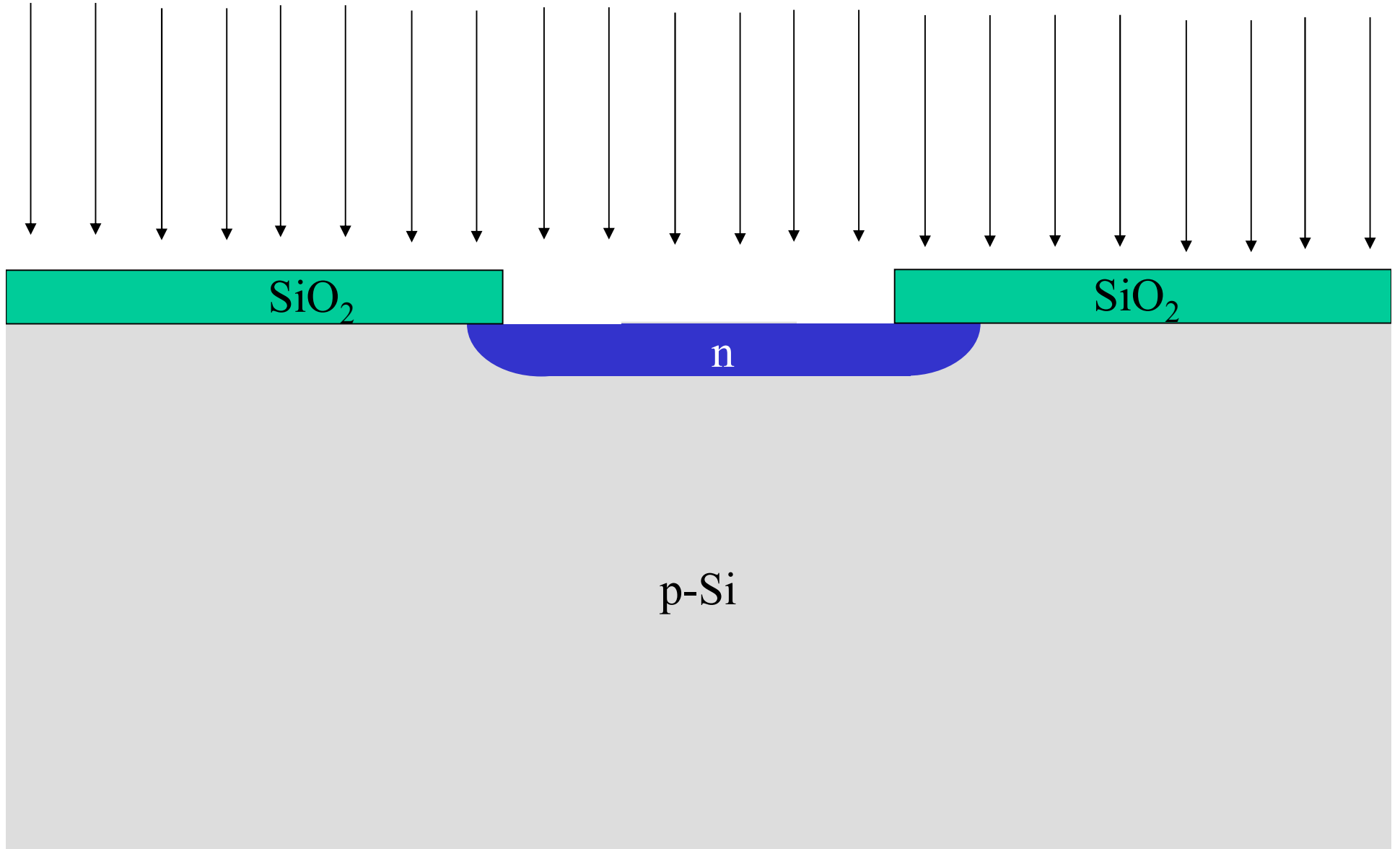


SiO₂

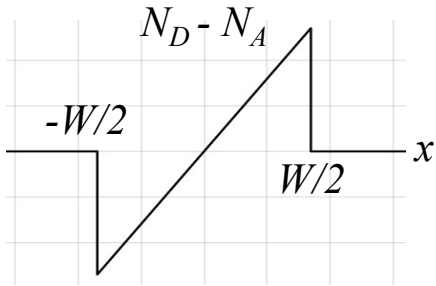
SiO₂

p-Si

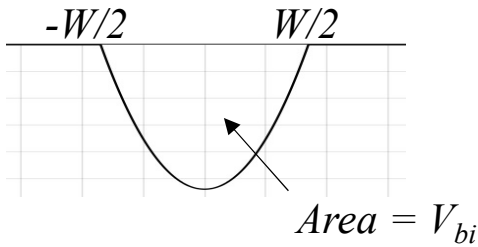
Diffuse or Implant



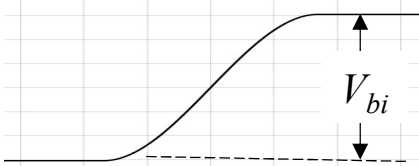
linearly graded junction



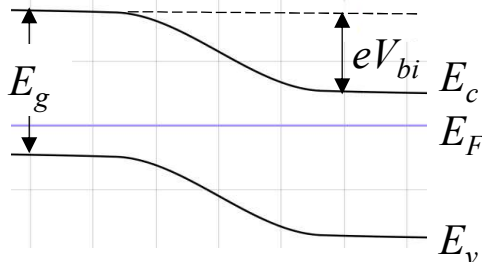
$$\rho = e(N_D(x) - N_A(x)) = eax$$



$$E = \int \frac{\rho}{\epsilon} dx = \frac{-ea}{2\epsilon} \left(\left(\frac{W}{2} \right)^2 - x^2 \right) \quad E_{\max} = \frac{-eaW^2}{8\epsilon}$$

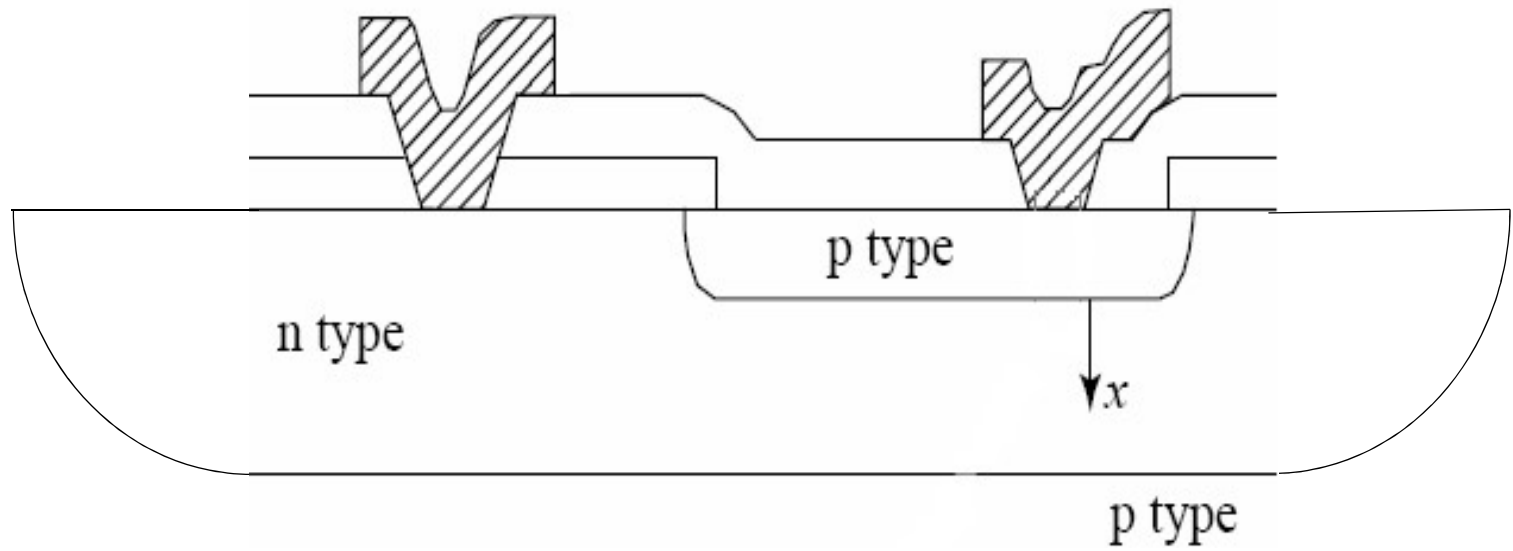


$$V = \int E dx = \frac{ea}{2\epsilon} \left(\left(\frac{W}{2} \right)^2 x - \frac{x^3}{3} \right)$$

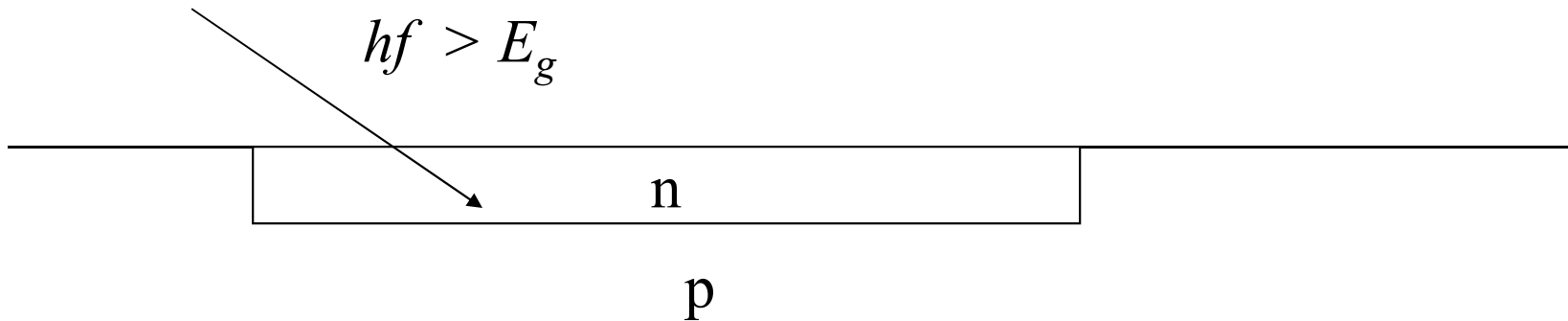


$$V_{bi} = \frac{eaW^3}{12\epsilon}$$

Isolation

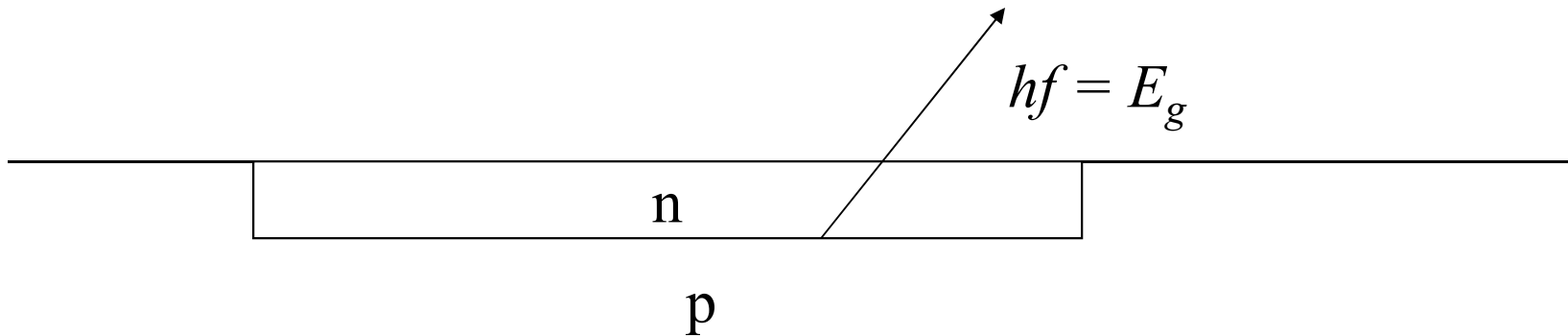


Solar cell



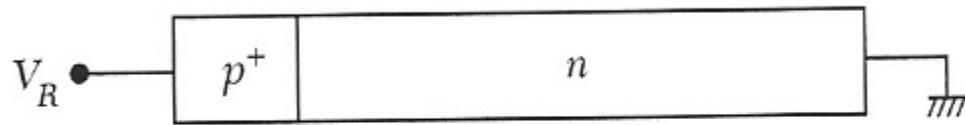
Light creates an electron-hole pair in the depletion region. The electric field sweeps the electrons towards the n-region and the holes towards the p-region.

Light emitting diode



Electrons and holes are injected into the depletion region by forward biasing the junction. The electrons fall in the holes. For direct bandgap semiconductors, photons are emitted. For indirect bandgap semiconductors, phonons are emitted.

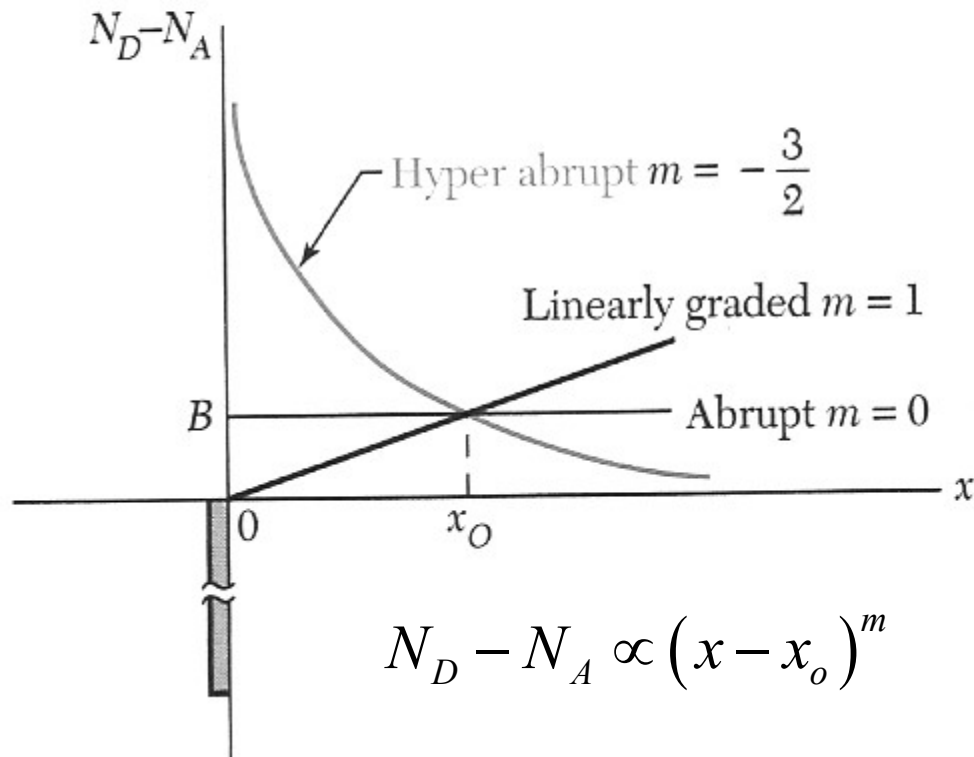
Varactor



$$C_j \propto (V_{bi} + V_R)^{-n}$$

abrupt: $n = 1/2$

linearly graded: $n = 1/3$



$$n = 1/(m+2)$$



Capacitance-voltage characteristics

specific capacitance $C_j = \frac{\epsilon}{W} \quad \text{F m}^{-2}$

abrupt junction: $W = \frac{\epsilon}{C_j} = \sqrt{\frac{2\epsilon(N_D + N_A)(V_{bi} - V)}{eN_D N_A}}$

a one sided abrupt junction in reverse bias:



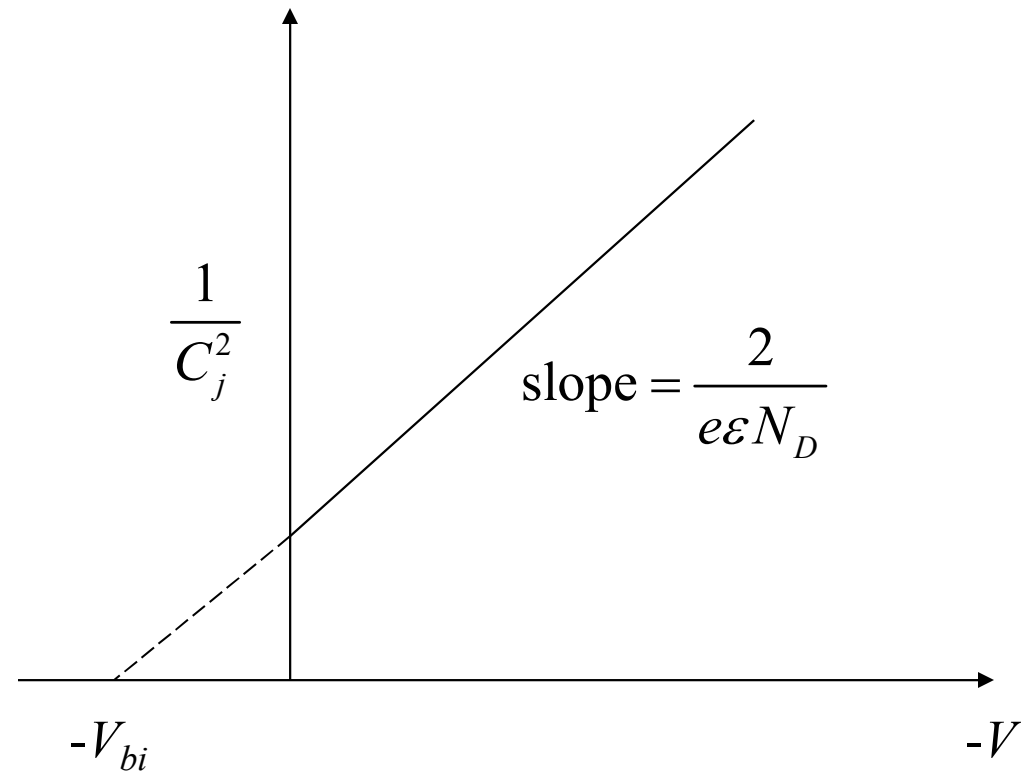
$$\frac{1}{C_j^2} = \frac{2(V_{bi} - V)}{e\epsilon N_D}$$

Capacitance-voltage characteristics

a one sided abrupt
junction in reverse
bias:

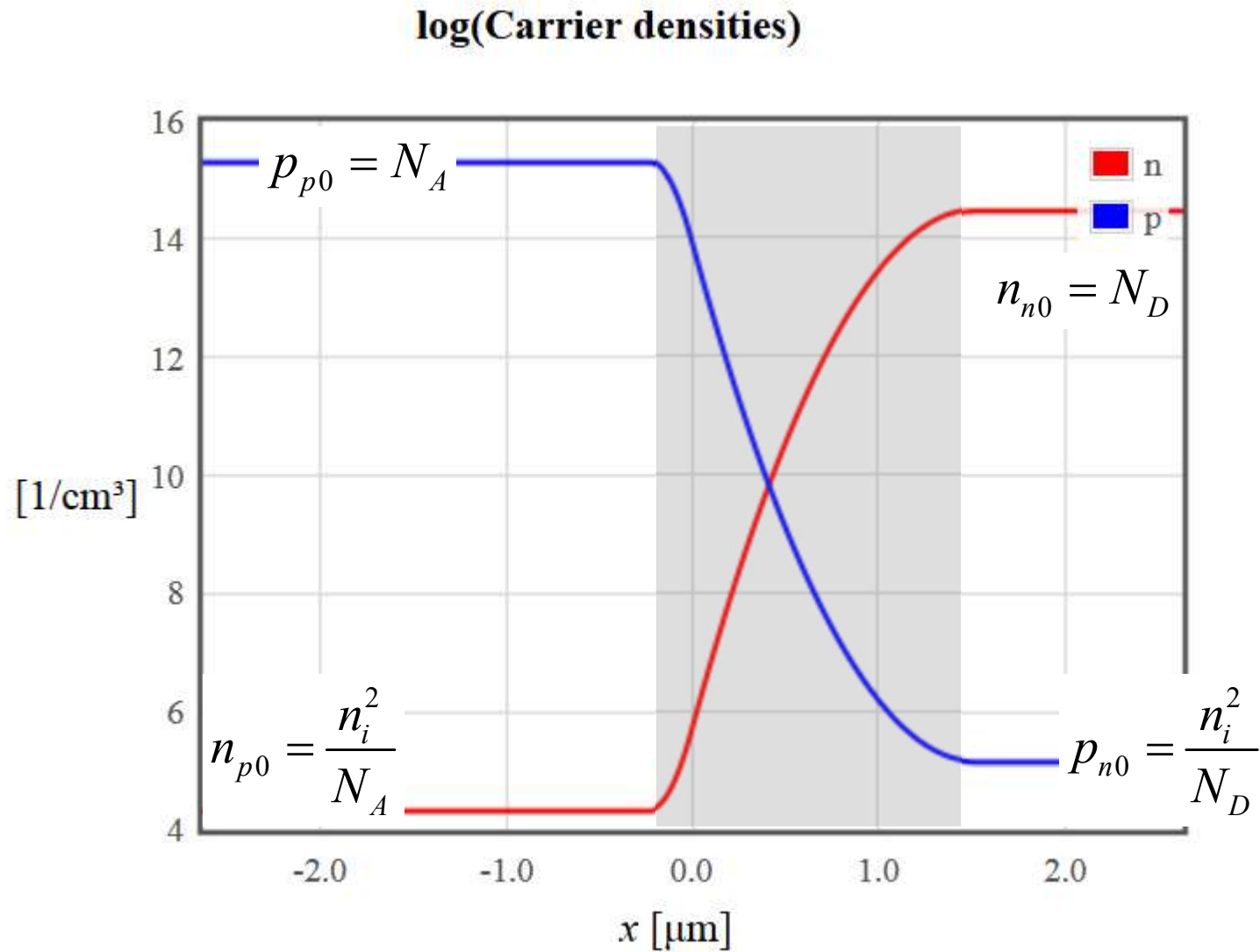
p^+	n
-------	-----

$$\frac{1}{C_j^2} = \frac{2(V_{bi} - V)}{e\epsilon N_D}$$



slope gives impurity concentration and the intercept gives V_{bi}

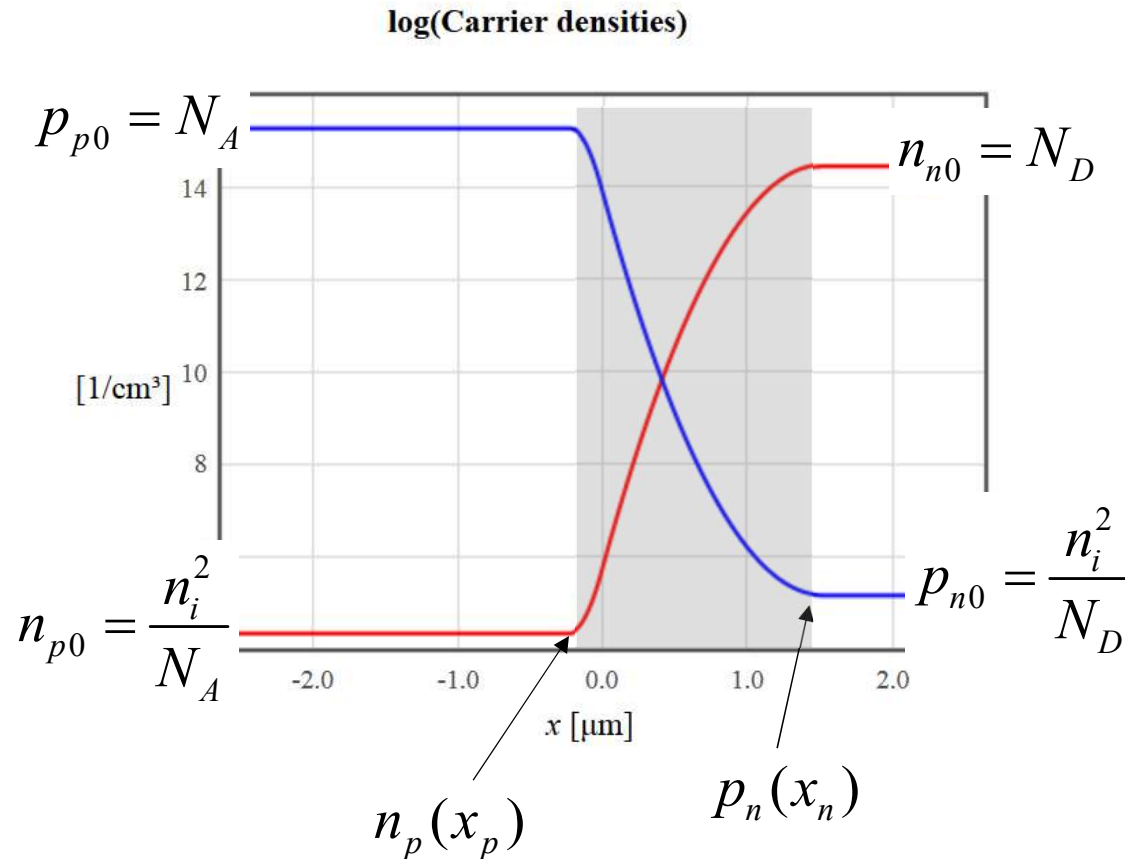
Equilibrium concentrations, $V = 0$



$$n_{p0}p_{p0} = n_{n0}p_{n0} = n_i^2$$

Bias voltage, $V = 0$

$$eV_{bi} = k_B T \ln\left(\frac{N_D N_A}{n_i^2}\right) = k_B T \ln\left(\frac{N_D}{n_{p0}}\right) = k_B T \ln\left(\frac{N_A}{p_{n0}}\right)$$



$$n_{p0} p_{p0} = n_{n0} p_{n0} = n_i^2$$

$V = 0$

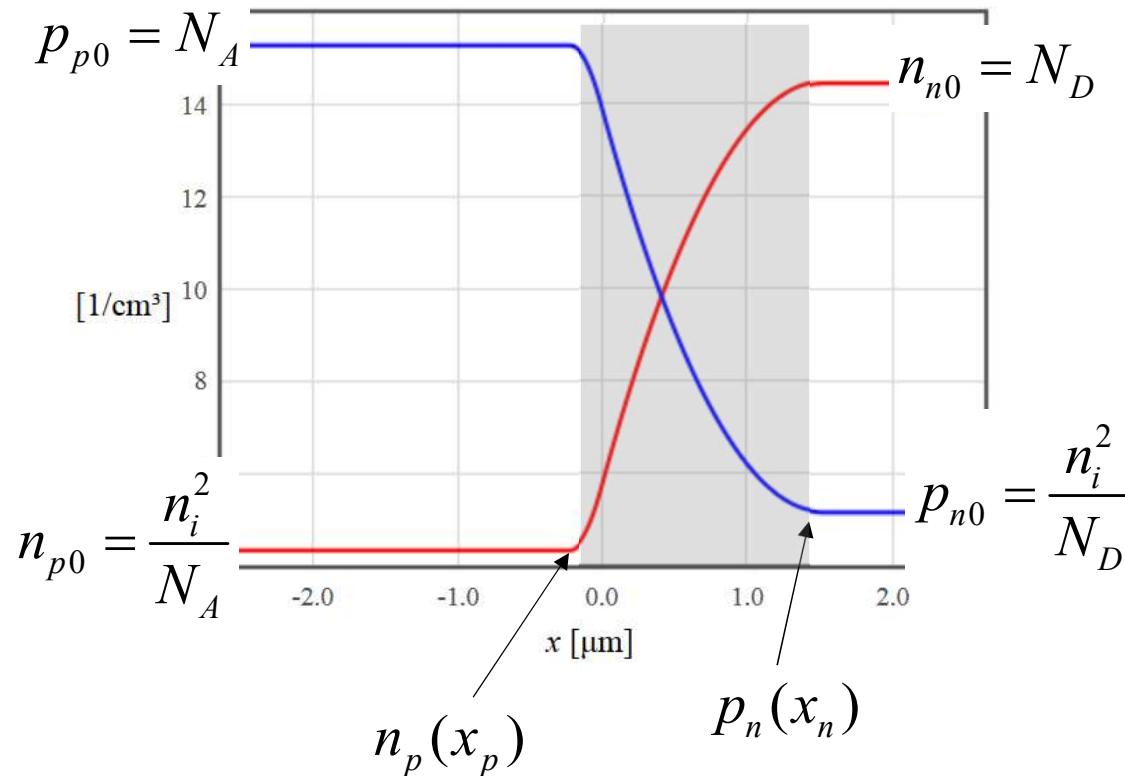
$$n_{p0} = N_D \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

$$p_{n0} = N_A \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

Bias voltage, $V \neq 0$

$$eV_{bi} = k_B T \ln \left(\frac{N_D N_A}{n_i^2} \right) = k_B T \ln \left(\frac{N_D}{n_{p0}} \right) = k_B T \ln \left(\frac{N_A}{p_{n0}} \right)$$

log(Carrier densities)



$$n_{p0} p_{p0} = n_{n0} p_{n0} = n_i^2$$

$V = 0$

$$n_{p0} = N_D \exp \left(\frac{-eV_{bi}}{k_B T} \right)$$

$$p_{n0} = N_A \exp \left(\frac{-eV_{bi}}{k_B T} \right)$$

$V \neq 0$

$$n_p(x_p) = N_D \exp \left(\frac{-e(V_{bi} - V)}{k_B T} \right)$$

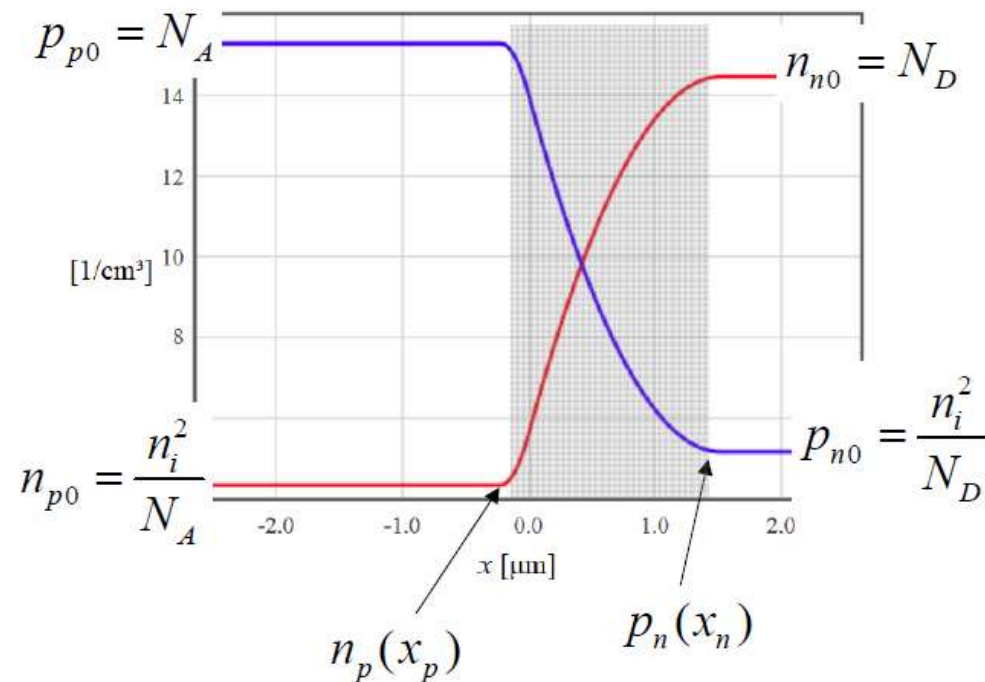
$$p_n(x_n) = N_A \exp \left(\frac{-e(V_{bi} - V)}{k_B T} \right)$$

Bias voltage, $V \neq 0$

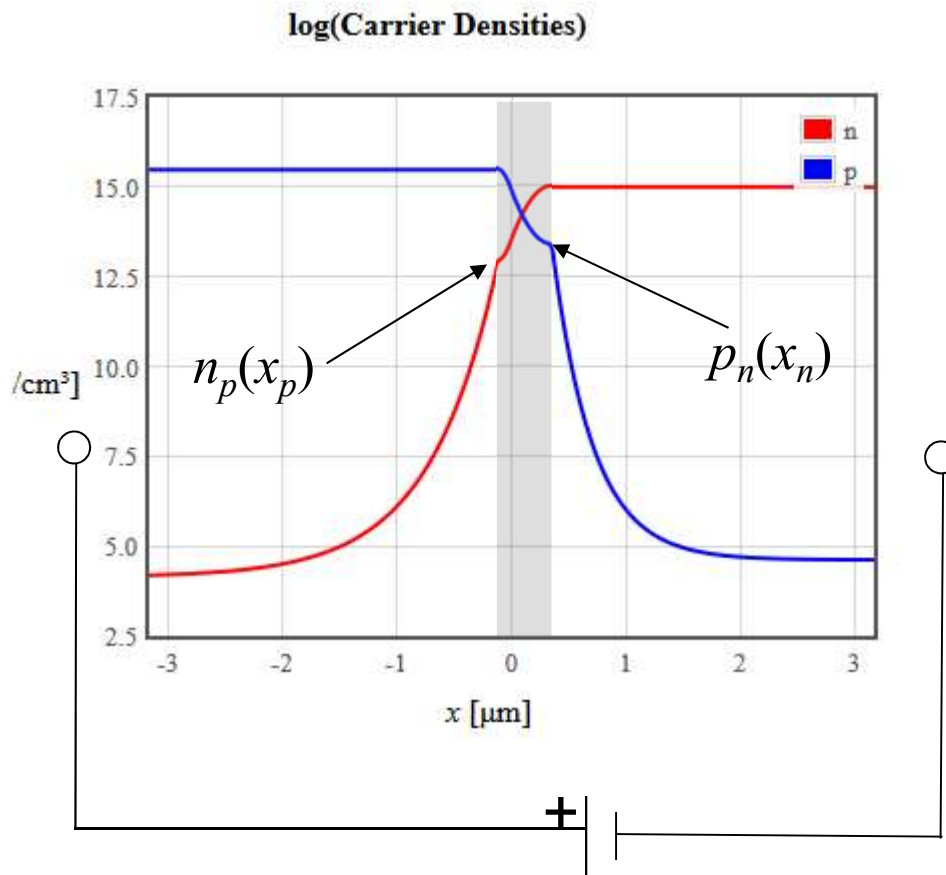
$$n_p(x_p) = N_D \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = N_A \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

log(Carrier densities)



Forward bias, $V > 0$



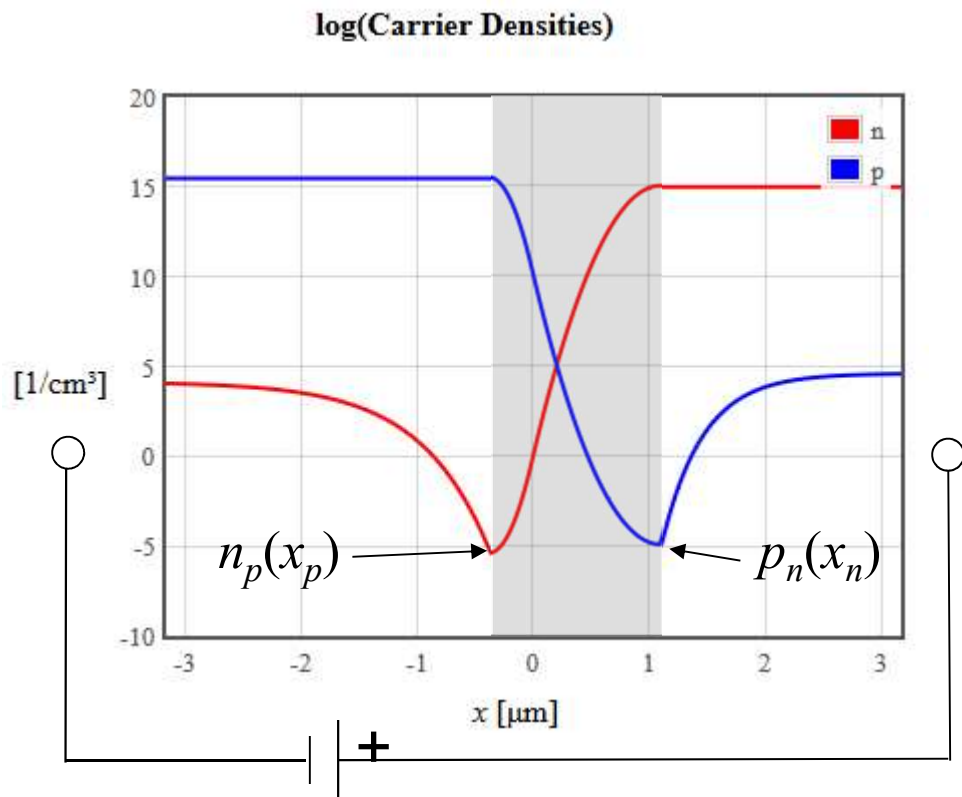
Electrons and holes are driven towards the junction.
The depletion region becomes narrower

$$n_p(x_p) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

Minority electrons are injected into the p-region
Minority holes are injected into the n-region

Reverse bias, $V < 0$



Electrons and holes are driven away from the junction.

The depletion region becomes wider

$$n_p(x_p) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

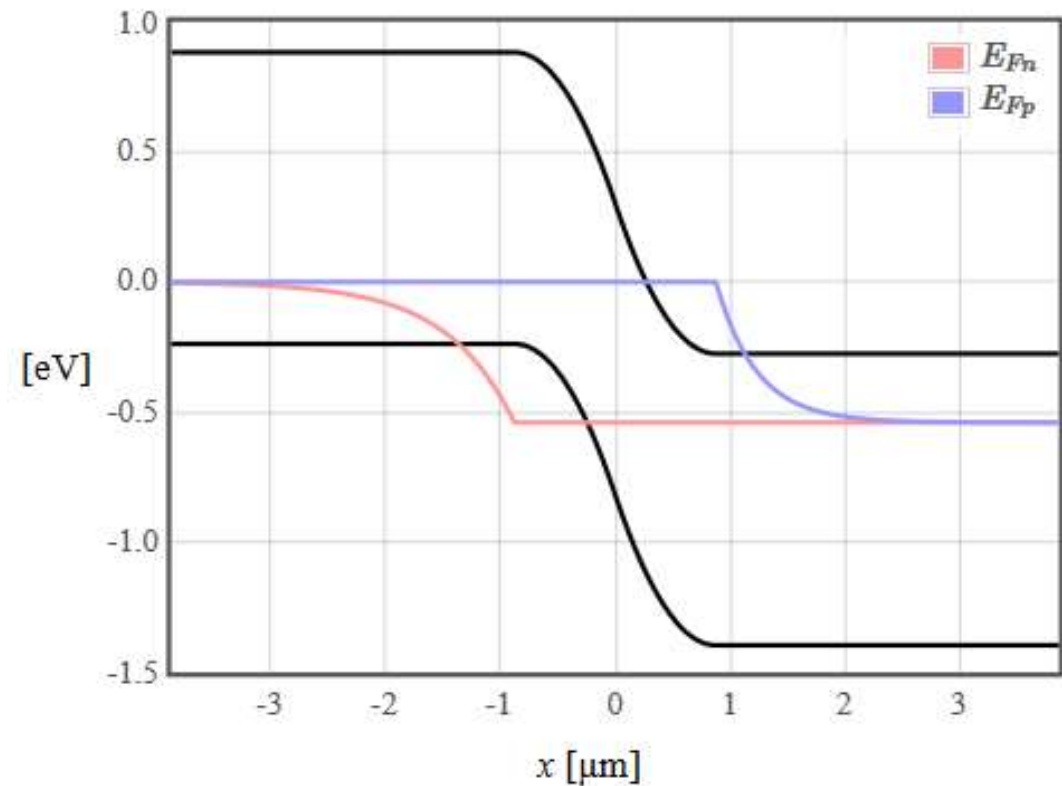
Minority electrons are extracted from the p-region by the electric field
Minority holes are extracted from the n-region by the electric field

Quasi Fermi level

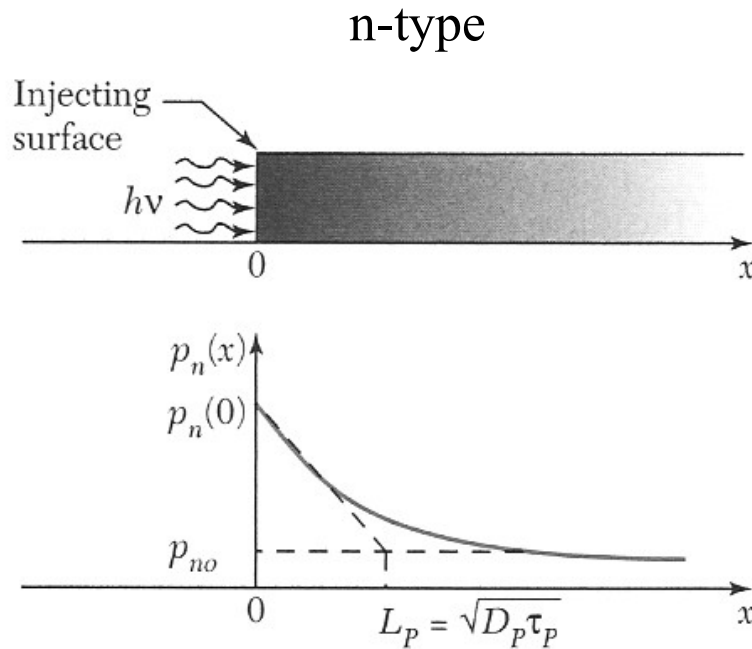
When the charge carriers are not in equilibrium the Fermi energy can be different for electrons and holes.

$$n = N_c \exp\left(\frac{E_{Fn} - E_c}{k_B T}\right)$$

$$p = N_v \exp\left(\frac{E_v - E_{Fp}}{k_B T}\right)$$



Review of Diffusion



$$D_p \frac{\partial^2 p_n}{\partial x^2} = \frac{p_n - p_{n0}}{\tau_p}$$

↑
recombination time

$$p_n(x) = p_{n0} + (p_n(0) - p_{n0}) \exp\left(\frac{-x}{L_p}\right)$$

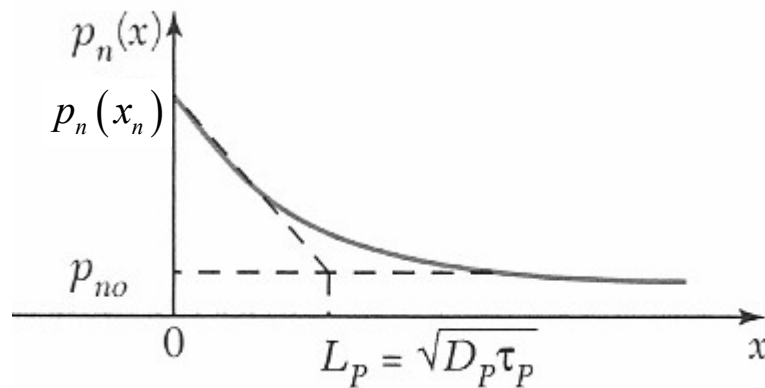
$$L_p = \sqrt{D_p \tau_p}$$

↑
diffusion length

Injection only occurs at the surface. There the minority carrier density is $p_n(0)$.

Diffusion current

n-type



$$p_n(x) = p_{n0} + (p_n(x_n) - p_{n0}) \exp\left(\frac{-x}{L_p}\right)$$

$$J_{diff,p} = -eD_p \frac{dp}{dx}$$


$$J_{diff,p} = -eD_p \frac{dp}{dx} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p} \exp\left(\frac{-x}{L_p}\right)$$

At the edge of the depletion region:

$$J_{diff,p} = -eD_p \frac{dp}{dx} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p}$$

Diffusion current

$$J_{diff,p} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p}$$



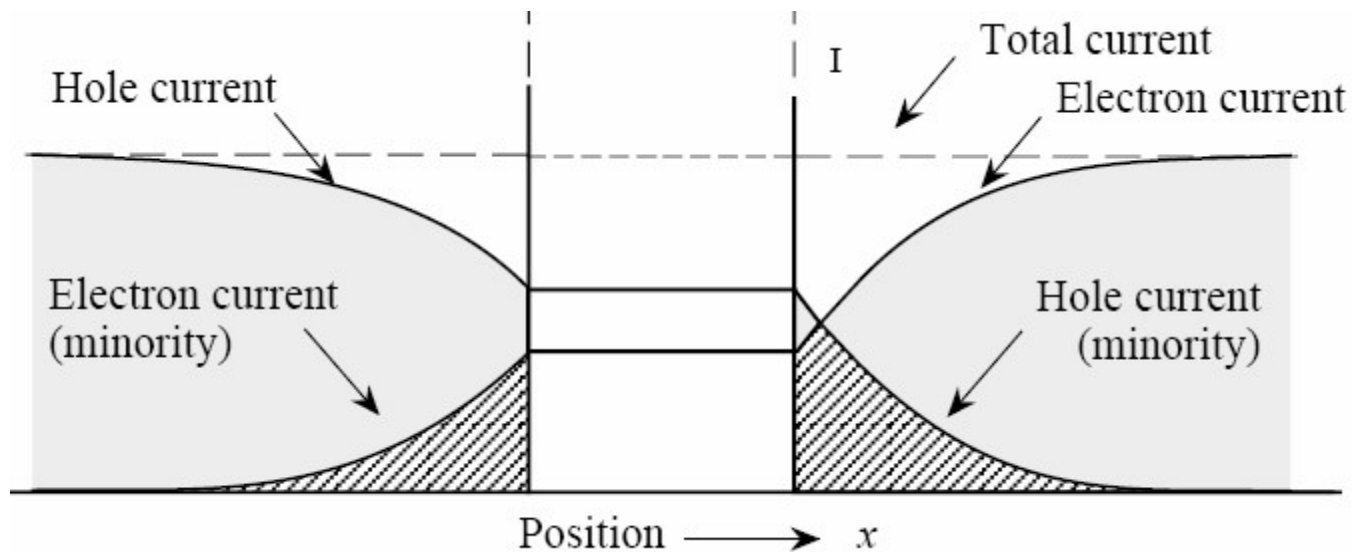
$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

$$J_{diff,p} = p_{n0} \frac{eD_p}{L_p} \left(\exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

Diffusion current

$$J_{diff,p} = \frac{p_{n0} e D_p}{L_p} \left(\exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

$$J_{diff,n} = \frac{n_{p0} e D_n}{L_n} \left(\exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

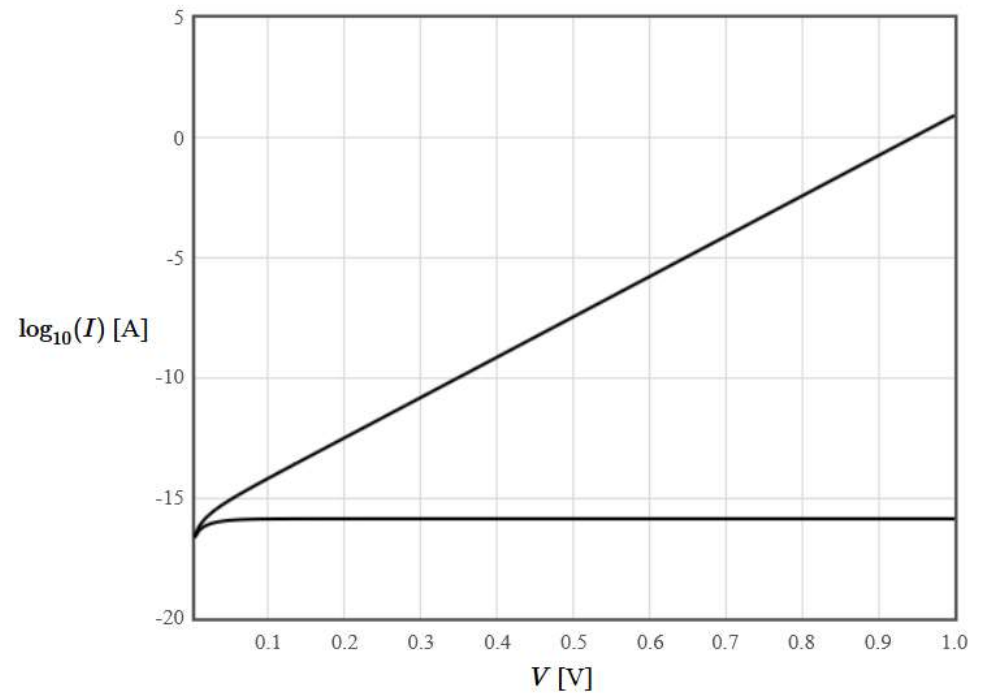
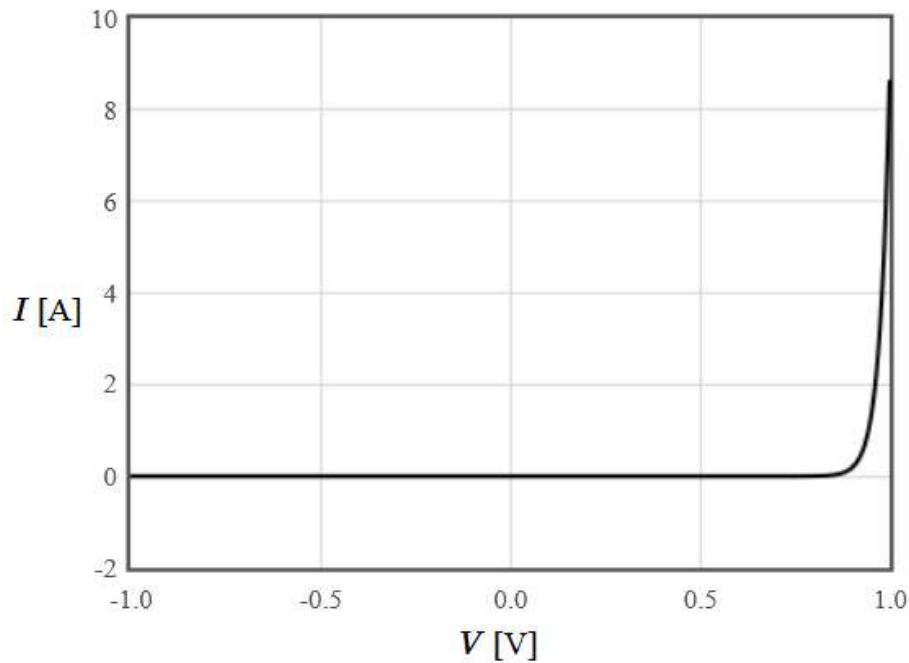


Diode current

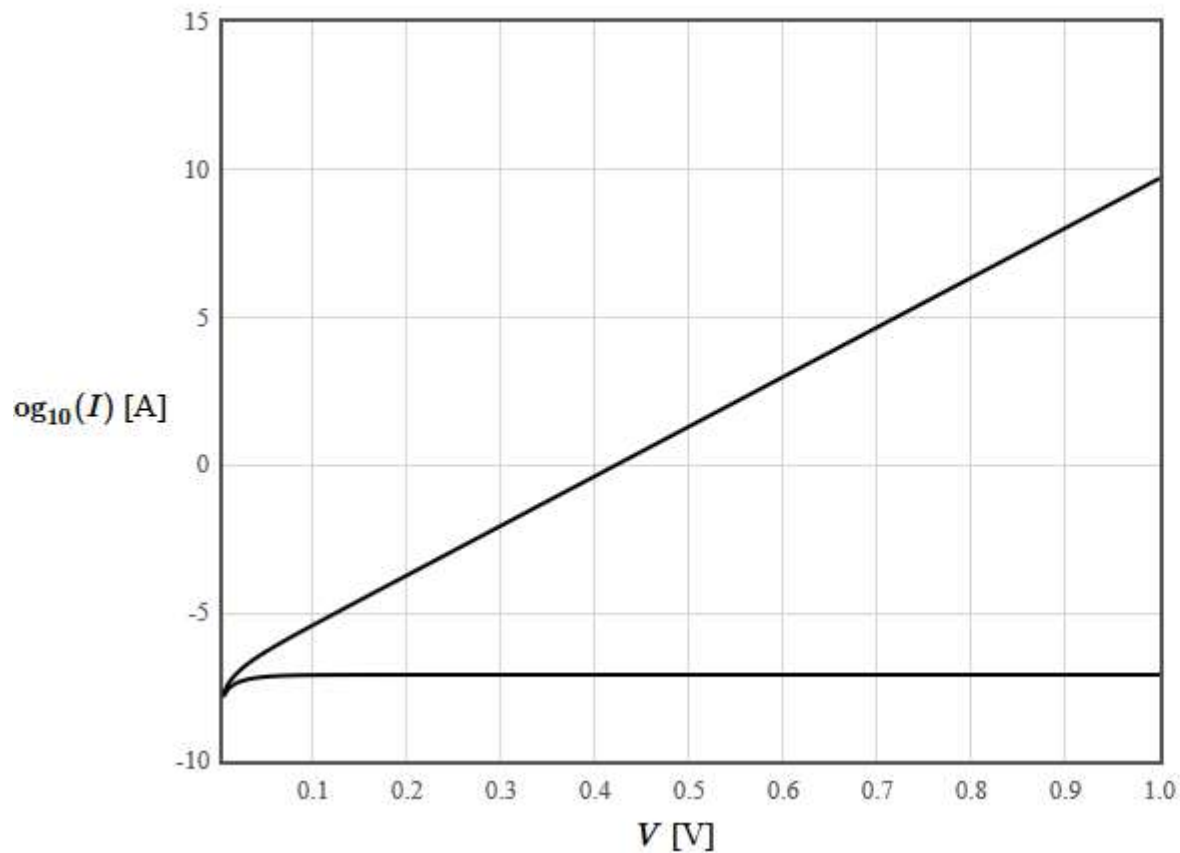
$$I = \underset{\substack{\uparrow \\ \text{Area}}}{eA} \left(\frac{p_{n0} D_p}{L_p} + \frac{n_{p0} D_n}{L_n} \right) \left(\exp\left(\frac{eV}{k_B T}\right) - 1 \right) = \underset{\substack{\uparrow \\ \text{Saturation current}}}{I_s} \left(\exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

Area

Saturation current



Diode I-V characteristics



$A = 1E-3$ cm²
 $N_c(300K) = 1.04E19$ cm⁻³
 $N_v(300K) = 6.0E18$ cm⁻³
 $E_g = 0.7437 - 4.77E-4 * T * T / (T + 235)$ eV

$\mu_p = 1900$ cm²/Vs
 $\tau_p = 1E-8$ s
 $N_a = 1E17$ cm⁻³

$\mu_n = 3900$ cm²/Vs
 $\tau_n = 1E-8$ s
 $N_d = 5E17$ cm⁻³

$T = 300$ K

Replot

Si Ge GaAs

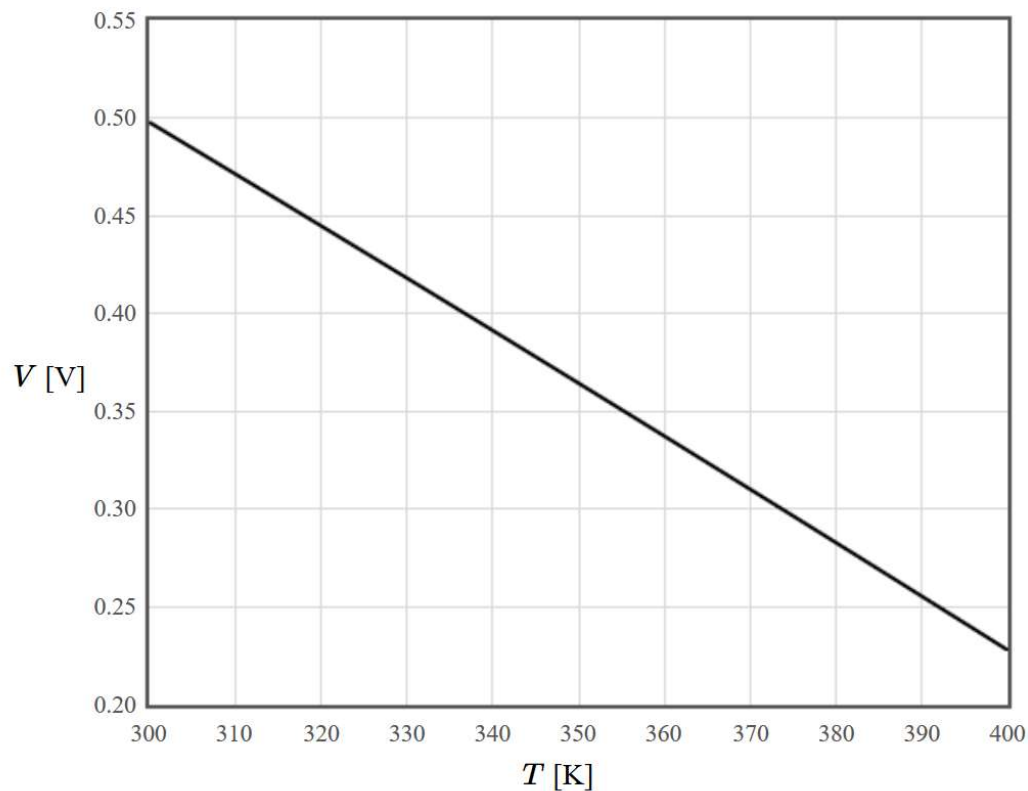
<http://lamp.tu-graz.ac.at/~hadley/psd/L6/pnIV.php>

Thermometer

$$I_S = Aen_i^2 \left(\frac{D_p}{L_p N_d} + \frac{D_n}{L_n N_a} \right)$$

$$n_i = \sqrt{N_c \left(\frac{T}{300} \right)^{3/2} N_v \left(\frac{T}{300} \right)^{3/2} \exp\left(\frac{-E_g}{2k_B T} \right)}$$

$$D_n = \frac{\mu_n k_B T}{e}$$



$A = 1E-3$ cm²
 $N_c(300K) = 2.78E19$ cm⁻³
 $N_v(300K) = 9.84E18$ cm⁻³
 $E_g = 1.166-4.73E-4*T*(T+636)$ eV

$\mu_p = 480$ cm²/Vs
 $\tau_p = 1E-8$ s
 $N_a = 1E17$ cm⁻³

$\mu_n = 1350$ cm²/Vs
 $\tau_n = 1E-8$ s
 $N_d = 5E17$ cm⁻³

$T_{start} = 300$ K
 $T_{stop} = 400$ K
 $I = 1E-6$ A

Replot
 Si Ge GaAs